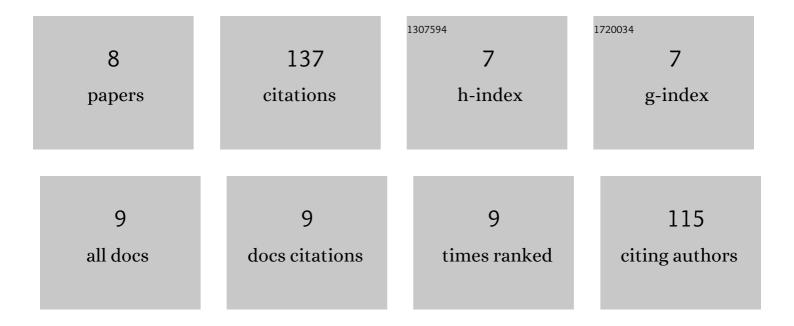
## Augustus K W Chee

List of Publications by Year in descending order

Source: https://exaly.com/author-pdf/3372547/publications.pdf Version: 2024-02-01



#	Article	IF	CITATIONS
1	Unravelling new principles of site-selective doping contrast in the dual-beam focused ion beam/scanning electron microscope. Ultramicroscopy, 2020, 213, 112947.	1.9	10
2	Principles of High-Resolution Dopant Profiling in the Scanning Helium Ion Microscope, Image Widths, and Surface Band Bending. IEEE Transactions on Electron Devices, 2019, 66, 4883-4887.	3.0	14
3	Enhancing doping contrast and optimising quantification in the scanning electron microscope by surface treatment and Fermi level pinning. Scientific Reports, 2018, 8, 5247.	3.3	21
4	Fermi level pinning characterisation on ammonium fluoride-treated surfaces of silicon by energy-filtered doping contrast in the scanning electron microscope. Scientific Reports, 2016, 6, 32003.	3.3	11
5	Quantitative Dopant Profiling by Energy Filtering in the Scanning Electron Microscope. IEEE Transactions on Device and Materials Reliability, 2016, 16, 138-148.	2.0	26
6	Dopant profiling based on scanning electron and helium ion microscopy. Ultramicroscopy, 2016, 161, 51-58.	1.9	7
7	A comparison of donor mapping techniques using the scanning helium ion microscope and scanning electron microscope. , 2014, , .		1
8	A quantitative model for doping contrast in the scanning electron microscope using calculated potential distributions and Monte Carlo simulations. Journal of Applied Physics, 2011, 109, .	2.5	47